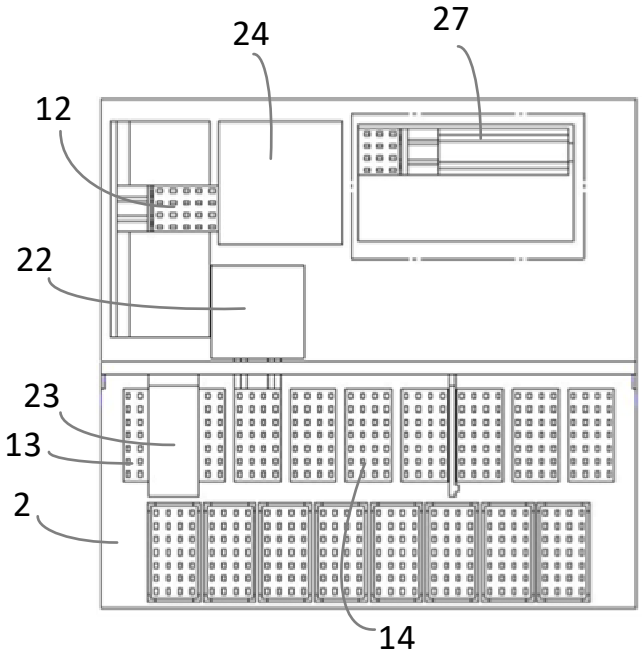


Fig. 1

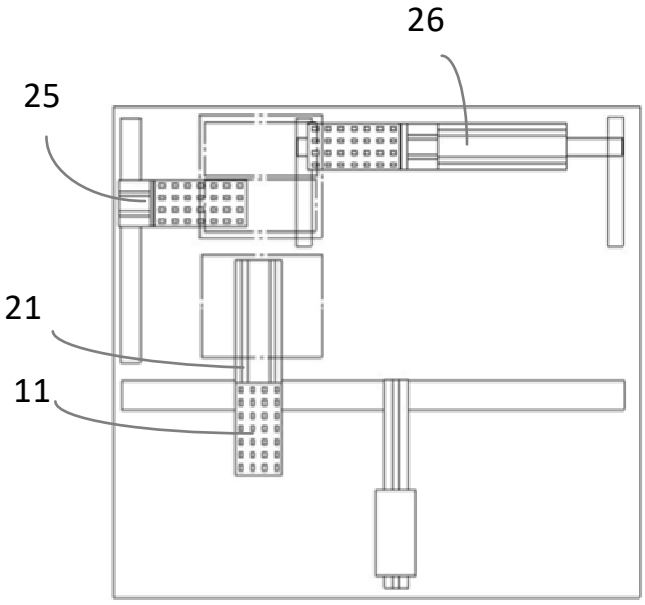


Fig. 2

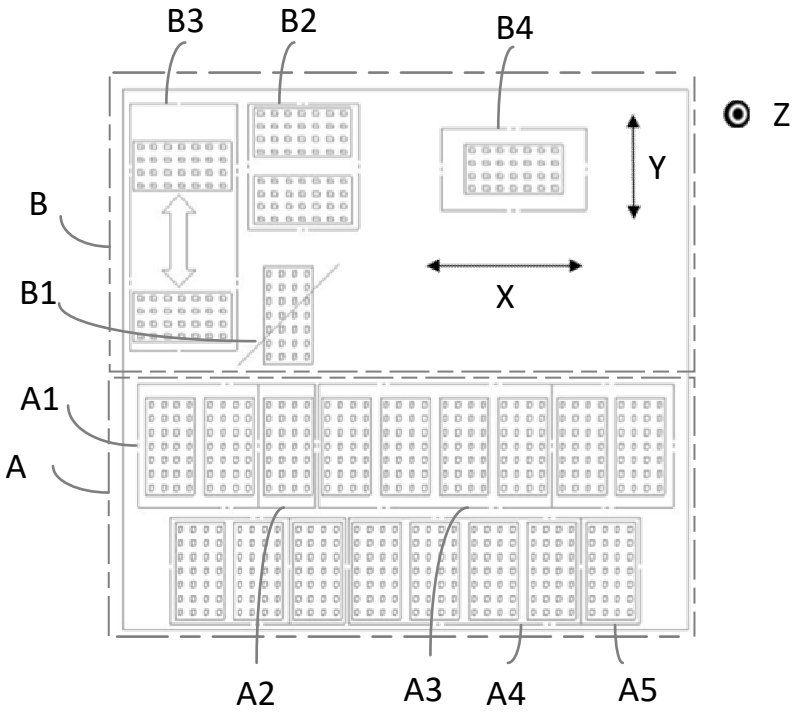

B3
B2
B4
Z
Y
B
X
B1
A1
A
A2
A3
A4
A5

Fig. 3

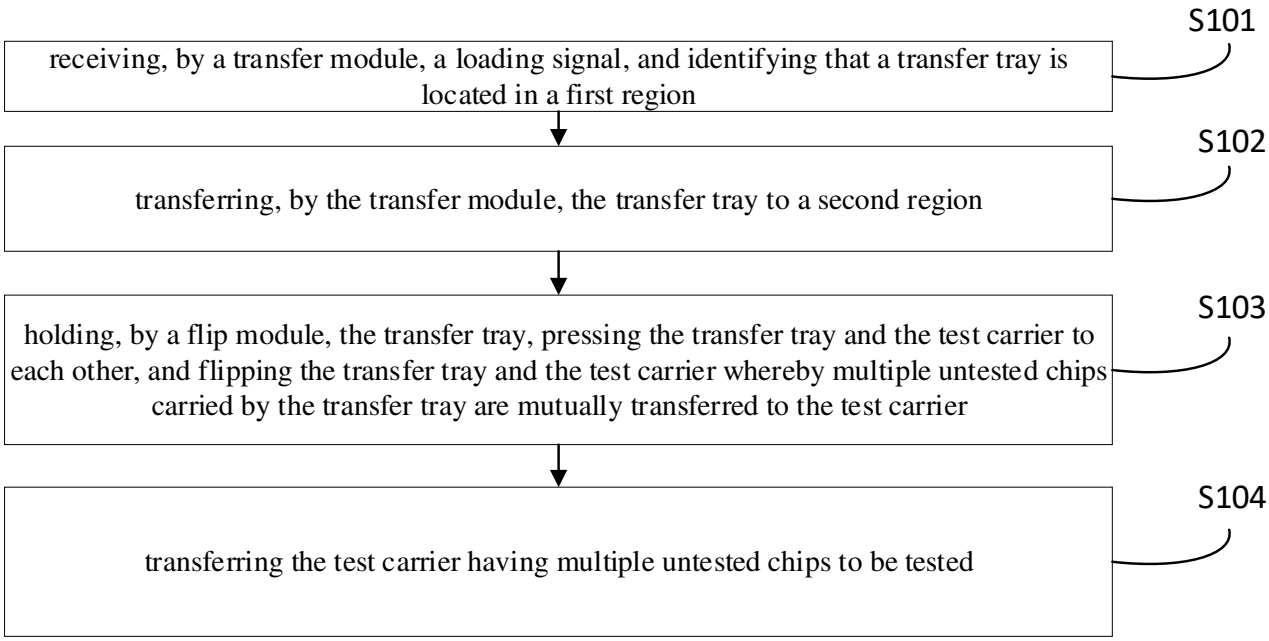

S101
receiving, by a transfer module, a loading signal, and identifying that a transfer tray is located in a first region
S102
transferring, by the transfer module, the transfer tray to a second region
S103
holding, by a flip module, the transfer tray, pressing the transfer tray and the test carrier to each other, and flipping the transfer tray and the test carrier whereby multiple untested chips carried by the transfer tray are mutually transferred to the test carrier
S104
transferring the test carrier having multiple untested chips to be tested

Fig. 4

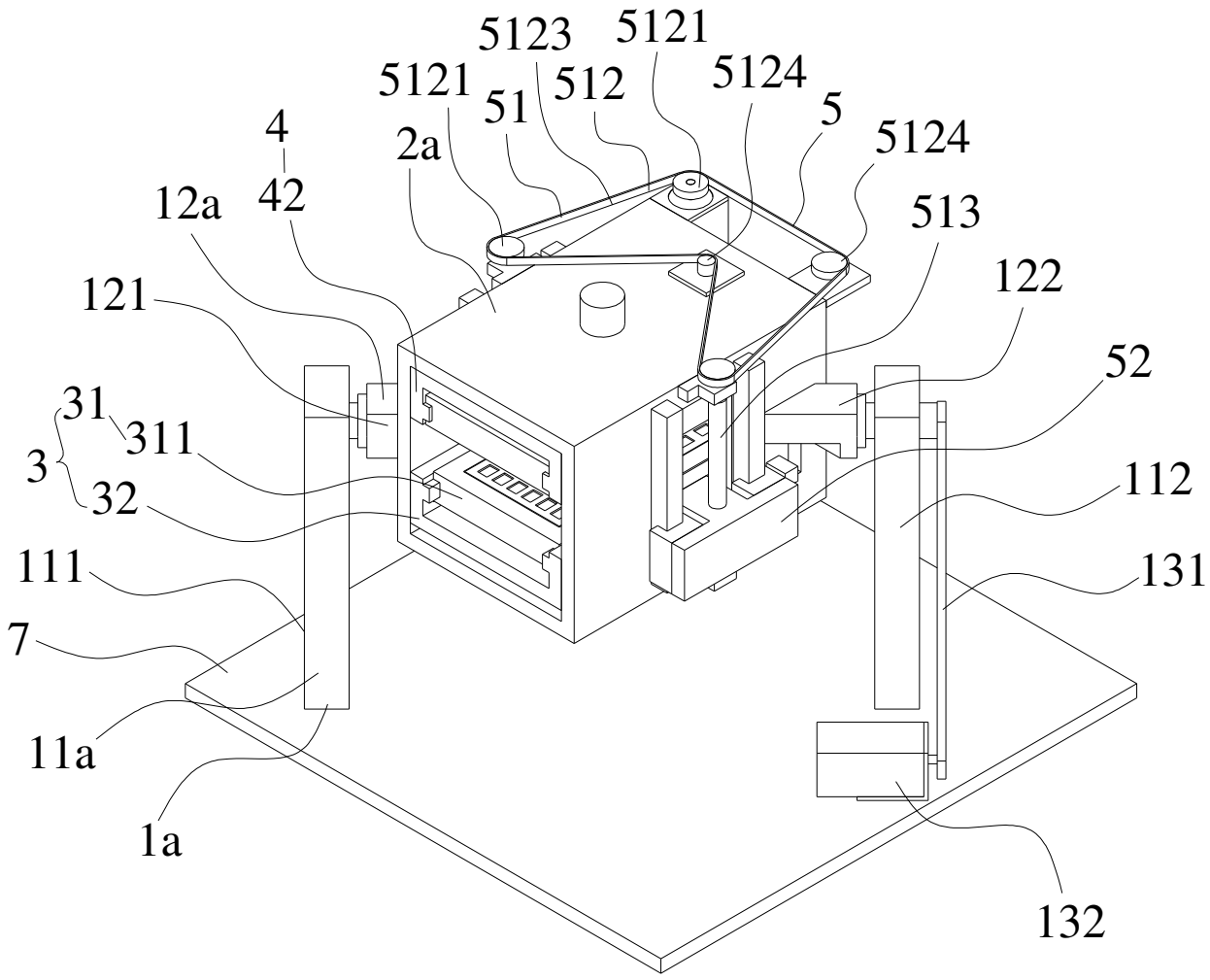

5123
5121
5121
5124
512
51
5
5124
4
2a
42
12a
513
121
122
52
31
311
3
32
112
111
131
7
11a
1a
132

Fig. 5

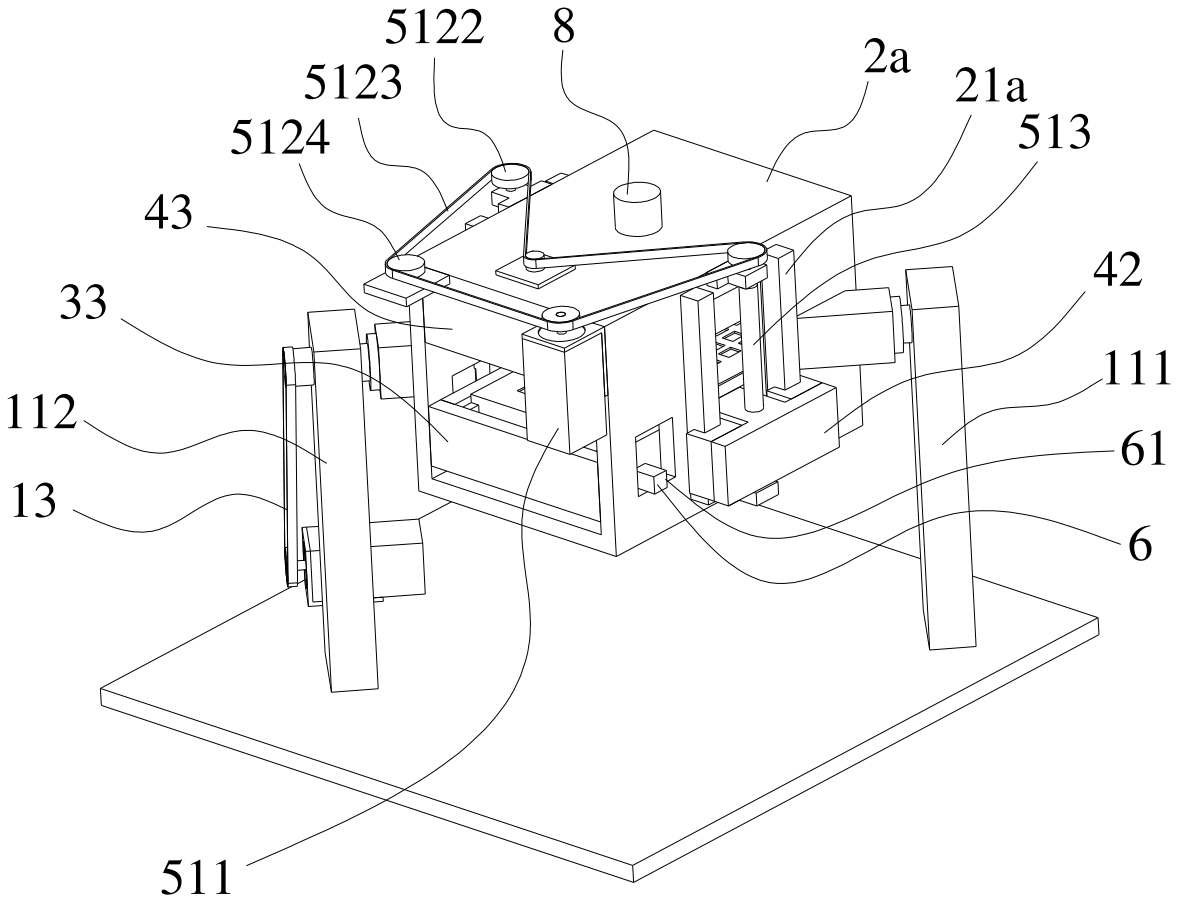


Fig. 6

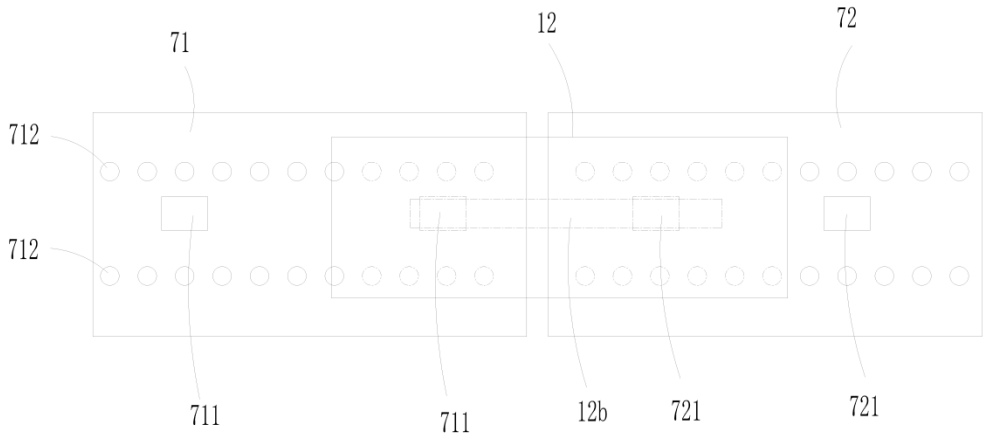


Fig. 7